IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of:

Joachim STUMPE et al.

International Appln: PCT/EP2004/005911

Filed: June 1, 2003

U.S. Application No.: Not Yet Assigned

For: METHOD AND DEVICE FOR

THREE-DIMENSIONALLY
DETERMINING THE REFRACTIVE

INDEX OF TRANSPARENT OR PARTIALLY TRANSPARENT

LAYERS

Art Unit: Not Yet Assigned

Examiner: Not Yet Assigned

Confirmation No.: Not Yet Assigned

Atty. Docket No.: 31583-226294 RK

Customer No.: 26694

Information Disclosure Statement

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

This is an Information Disclosure Statement submitted under 37 C.F.R. § 1.97 within the time specified under 37 C.F.R. § 1.97(c).

In order to comply the duty of disclosure pursuant to 37 C.F.R. § 1.56, submitted herewith is a Form PTO/SB/08A listing the documents cited in the international application and in the International Search Report of International Application No. <u>PCT/EP2004/005911</u>. The relevance of each document is indicated therein.

Copies of the documents cited in the International Search Report are not being provided since copies are furnished directly by WIPO under an exchange program between the PTO, the EPO and the JPO.

If the copies of the documents cited in the International Search Report were not furnished and a copy of each cited document is desired, please inform the undersigned and a copy of the missing documents will be supplied.

10/559650 IAP9 Rec'd PCT/PTO 05 DEC 2005

Applicant(s): Joachim STUMPE et al. Atty. Docket: 31583-226294 RK

In view of the above, no further statement of relevance need be given, and as all requirements of 37 C.F.R. § 1.97 and § 1.98, and all official guidelines pertaining to Information Disclosure Statements have been complied with, it is respectfully requested that the Examiner consider the cited publications and make them of record.

Respectfully submitted,

Date: December 5, 2005

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PTO/SB/08A (08-00)
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Substitute	for form 1449A/PTO	•		<u>l</u>	APS Rec'd POT/PTO 05 DA
				Application Number	NOT YET ASSIGNED
INFO	RMATION	DIS	CLOSURE	Filing Date	Concurrently
STATEMENT BY APPLICANT				First Named Inventor	Joachim STUMPE et al.
				Prior Group Art Unit	Not Yet Assigned
	(use as many she	ets as	necessary)	Prior Examiner Name	Not Yet Assigned
Sheet	1	of	2	Attorney Docket Number	31583-226294 RK

	U.S. PATENT DOCUMENTS									
		U.S. Patent Document	Name of Patentee or Applicant	Date of Publication of	Pages, Columns, Lines, Where Relevant					
Examiner Initials *	Cite No. ¹	Number Kind Code ² (if known)	of Cited Document	Cited Document MM-DD-YYYY	Passages or Relevant Figures Appear					
-	AA	3,963,348	ITO et al.	6/15/1976						
	AB	5,526,118	MIYAGAWA et al.	6/11/1996						

FOREIGN PATENT DOCUMENTS									
Examiner	Cite		eign Patent Docu	ment Kind	Name of Patentee or	Date of Publication of Cited	Pages, Columns, Lines, Where Relevant		
Initials*	No.¹	Office 3		Code ⁵ (if known)	Applicant of Cited Document	Document MM-DD-YYYY	Passages or Relevant Figures Appear	T ₆	
	AC	WO	01/42769		PRIESTLEY	6/14/2001			
	AD	JP	11 037937		RICOH CO. LTD.	2/12/1999			
	AE	JP	03 195905		AISIN SEIKI CO. LTD.	8/27/1991			
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	Substitut	e for	r form 1449A/PT)		Complete if Known		
	INIEC	, D	RA A TION	DIC	CL OCUBE	Application Number	NOT YET ASSIGNED	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT						Filing Date	Concurrently	
					PPLICANT	First Named Inventor	Joachim STUMPE et al.	
						Group Art Unit	Not Yet Assigned	
(use as many sheets as necessary)						Examiner Name	Not Yet Assigned	
	Sheet		2	of	2	Attorney Docket Number	31583-226294 RK	

		OTHER PRIOR ART NON PATENT LITERATURE DOCUMENTS	
Examiner Initials *	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T 2
	AF	RAMSDALE et al., "Ellipsometric Determination of Anisotropic Optical Constants In Electroluminescent Conjugated Polymers", Advanced Materials, VCH, Verlagsgesellschaft, Weinheim, DE, vol. 14, no. 3, 5 February 2002, pp. 212-215	
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	AK	Patent Abstracts of Japan, vol. 1999, No. 05, 31 May 1999	
	AL	Patent Abstracts of Japan, vol. 015, No. 460, 21 November 1991	

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